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# Temperature stable $\text{K}_{0.5}(\text{Nd}_{1-x}\text{Bi}_x)_{0.5}\text{MoO}_4$ microwave dielectrics ceramics with ultra-low sintering temperature

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## Abstract

$K_{0.5}(Nd_{1-x}Bi_x)_{0.5}MoO_4$  ( $0.2 \leq x \leq 0.7$ ) ceramics were prepared via the solid state reaction method. All ceramics densified below 720 °C with a uniform microstructure. As  $x$  increased from 0.2 to 0.7, relative permittivity ( $\epsilon_r$ ) increased from 13.6 to 26.2 commensurate with **an increase in temperature coefficient of resonant frequency (TCF)** from  $-31$  ppm/°C to  $+60$  ppm/°C and a decrease in Qf value (Q = quality factor; f = resonant frequency) from 23,400 GHz to 8,620 GHz. Optimum TCF was obtained for  $x = 0.3$  ( $-15$  ppm/°C) and  $0.4$  ( $+4$  ppm/°C) sintered at 660 and 620 °C with  $\epsilon_r \sim 15.4$ , Qf  $\sim 19,650$  GHz, and  $\epsilon_r \sim 17.3$ , Qf  $\sim 13,050$  GHz, respectively. Ceramics in this novel solid solution are a candidate for ultra low temperature co-fired ceramic (ULTCC) technology.

# 1. INTRODUCTION

Due to the requirements of miniaturization and integration, low temperature co-fired ceramic (LTCC) technology plays an important role in the fabrication of modern electronic components. For LTCC technology, microwave dielectric ceramics/composites are required whose sintering temperatures are lower than the melting point (M.P.) of the internal electrode. Silver is the most commonly used internal electrode with M.P.  $\sim 961$  °C.<sup>1-6</sup> The search for microwave dielectrics with low intrinsic sintering temperature has attracted much attention and the subject is now referred to ultra-low temperature co-fired ceramics (ULTCC). Since densification temperature is strongly related to M.P., ULTCCs are usually rich in oxides such as TeO<sub>2</sub> (733°C), MoO<sub>3</sub> (795 °C), Bi<sub>2</sub>O<sub>3</sub> (817°C) and V<sub>2</sub>O<sub>5</sub> (690°C).<sup>7-15</sup> However, most single phase ULTCCs possess a large negative or positive temperature coefficient of resonant frequency (TCF) and solid solutions or composites are needed to tune TCF to zero.<sup>16,17</sup> As reported previously,<sup>18</sup> the K<sub>1/2</sub>Bi<sub>1/2</sub>MoO<sub>4</sub> ceramic, which adopts an A site ordered monoclinic scheelite-related structure, may be densified at 630 °C with a permittivity ( $\epsilon_r$ ) = 37, a quality factor (Qf)  $\sim 4,000$  GHz and a large positive TCF = + 117 ppm/°C. Although it is chemically compatible with aluminum (M. P.  $\sim 660$  °C), its large TCF requires tuning. Lanthanide ions ( $R_{Ln} = 0.99-1.16$  Å for CN8) partially substitute for Bi<sup>3+</sup> ( $R_{Bi} = 1.17$  Å for CN8) in many systems.<sup>19-21</sup> In previous work,<sup>22</sup> (K<sub>0.5</sub>Nd<sub>0.5</sub>)MoO<sub>4</sub> was also reported to crystallize in a A-site ordered scheelite structure but with TCF  $\sim -62$  ppm/°C and thus constitutes an ideal end member in a solid solution with K<sub>1/2</sub>Bi<sub>1/2</sub>MoO<sub>4</sub> to create temperature stable compositions. In the present work, the sintering, crystal structure, microstructure and microwave dielectric properties of the K<sub>0.5</sub>(Nd<sub>1-x</sub>Bi<sub>x</sub>)<sub>0.5</sub>MoO<sub>4</sub> ( $0.2 \leq x \leq 0.7$ ) ceramics were studied.

## 2. EXPERIMENTAL

Proportionate amounts of reagent-grade starting materials of Bi<sub>2</sub>O<sub>3</sub> (> 99 %, Shu-Du Powders Co. Ltd., Chengdu, China), K<sub>2</sub>CO<sub>3</sub>, Nd<sub>2</sub>O<sub>3</sub> (> 99 %, Sinopharm Chemical Reagent Co., Ltd, Shanghai, China) and MoO<sub>3</sub> (> 99 %, Fuchen Chemical Reagents, Tianjin, China) were measured according to the stoichiometric formulation [K<sub>0.5</sub>(Nd<sub>1-x</sub>Bi<sub>x</sub>)<sub>0.5</sub>]MoO<sub>4</sub> (x = 0.2, 0.3, 0.4 and 0.7). Ceramic samples were prepared via the traditional solid-state reaction method as described in our previous work.<sup>2,15</sup> Samples were calcined at 550 °C and sintered in air from 580 ~ 720 °C. Room temperature X-ray diffraction (XRD) was performed with Cu K $\alpha$  radiation (Rigaku D/MAX-2400 X-ray diffractometry, Tokyo, Japan). Prior to examination, sintered pellets were crushed in a mortar and pestle. Diffraction patterns were obtained between 2 $\theta$  of 5-65 ° at a step size of 0.02 °. To examine the grain morphology, as-fired and fractured surfaces were examined by scanning electron microscopy (SEM, FEI, Quanta 250 F). Density was measured using Archimedes' method. Dielectric properties at MW frequencies were measured with the TE<sub>018</sub> dielectric resonator method with a network analyzer (HP 8720 Network Analyzer, Hewlett-Packard) and a temperature chamber (Delta 9023, Delta Design, Poway, CA). The temperature coefficient of resonant frequency TCF ( $\tau_f$ ) was calculated with the following formula:

$$\text{TCF}(\tau_f) = \frac{f_T - f_{T_0}}{f_{T_0} \times (T - T_0)} \times 10^6 \quad (1)$$

where the  $f_T$  and  $f_{T_0}$  were the TE<sub>018</sub> resonant frequencies at temperature T and T<sub>0</sub>, respectively.

### 3. RESULTS AND DISCUSSIONS

XRD traces of  $K_{0.5}(Nd_{1-x}Bi_x)_{0.5}MoO_4$  with  $0.2 \leq x \leq 0.7$  calcined 4 h at 550 °C are shown in Fig. 1a. All samples crystallized in an A-site ordered monoclinic scheelite phase<sup>23</sup> with equivalent traces of sintered ceramics. Except for the main reflection peaks as indexed according to PDF card No. 32-0817, many super lattice reflection peaks were also observed, which is similar to the literature's report.<sup>23</sup> The strongest peak at 27.5 degree moved to lower  $2\theta$  with the increase of  $Bi^{3+}$  concentration due to its larger ionic radius (1.17 Å) than  $Nd^{3+}$  (1.109 Å).<sup>24</sup> As shown in Fig. 1b, a increased linearly with x while b decreased. The non-contiguous behavior of a and b reflects further deformation of the monoclinic structure caused by  $Bi^{3+}$  substitution of  $Nd^{3+}$ , and is commensurate with an increase in gamma, as shown in Fig. 1c. Nonetheless,  $Bi^{3+}$  substitution for  $Nd^{3+}$  resulted in a linear increase in cell volume.

SEM images of the  $K_{0.5}(Nd_{1-x}Bi_x)_{0.5}MoO_4$  ceramics sintered at their optimal temperature are shown in Fig. 2. The end members,  $(K_{0.5}Nd_{0.5})MoO_4$  and  $(K_{0.5}Bi_{0.5})MoO_4$ , sintered at 720 °C and 630 °C, respectively but for the  $K_{0.5}(Nd_{1-x}Bi_x)_{0.5}MoO_4$  solid solutions, Bi substitution lowered the sintering temperature from 720 °C for  $x = 0.2$  to 580 °C for  $x = 0.7$ . A homogenous microstructure was retained for all compositions with grain size, 1 ~ 3 μm, in agreement with previous reports.<sup>18,22</sup> Relative densities of all the ceramic samples are above 95 % as measured by Archimedes' method.

$\epsilon_r$ , Qf and TCF of the  $K_{0.5}(Nd_{1-x}Bi_x)_{0.5}MoO_4$  ( $0.2 \leq x \leq 0.7$ ) ceramics as a function

of sintering temperature and composition are shown in Fig. 3.  $\epsilon_r$  increased with sintering temperature and saturated above optimal densification whilst Qf achieved a maximum in a narrow range of sintering temperature. According to Shannon's additive rule,<sup>25</sup> polarizability of  $\text{Bi}^{3+}$  and  $\text{Nd}^{3+}$  in the MW region are  $6.12 \text{ \AA}^3$  and  $5.01 \text{ \AA}^3$ , respectively. Hence,  $\epsilon_r$  increased linearly from 9.8 to 37 from  $x = 0 - 1$  while TCF tuned linearly from  $-62 \text{ ppm/}^\circ\text{C}$  to  $+117 \text{ ppm/}^\circ\text{C}$ . Near zero TCF was obtained for  $0.3 \leq x \leq 0.4$ . However, Qf exponentially decayed with x. According to the classic oscillator model, Qf value is inversely proportional to permittivity value as shown in the following:

$$Q \times f \approx \frac{(ze)^2 / mV\epsilon_0}{2\pi\gamma \times (\epsilon'(\omega) - \epsilon(\infty))} \quad (2)$$

in which  $\epsilon'(\omega)$  is the real part of permittivity,  $\epsilon(\infty)$  is the electronic part of the static permittivity,  $\gamma$  is the damping parameter, z is the equivalent electric charge number, e is the electric charge for a electron, m is the equivalent atom weight and V is the unit volume. This relation explains well the trend of Qf value versus x value. Optimum MW properties were obtained for  $\text{K}_{0.5}(\text{Nd}_{0.3}\text{Bi}_{0.2})\text{MoO}_4$  ( $x = 0.4$ ) ceramics sintered at  $620 \text{ }^\circ\text{C}$  with  $\epsilon_r \sim 17.3$ , Qf  $\sim 13,050 \text{ GHz}$  and TCF  $\sim +4 \text{ ppm/}^\circ\text{C}$  and for  $\text{K}_{0.5}(\text{Nd}_{0.35}\text{Bi}_{0.15})\text{MoO}_4$  ( $x = 0.3$ ) ceramics sintered at  $660 \text{ }^\circ\text{C}$  with  $\epsilon_r \sim 15.4$ , Qf  $\sim 19,650 \text{ GHz}$  and TCF  $\sim -15 \text{ ppm/}^\circ\text{C}$ . A comparison of microwave dielectric ceramics with similar permittivities are listed in Table I.<sup>26-29</sup> Compared with other LTCC microwave dielectric ceramics, the TCF values of the  $\text{K}_{0.5}(\text{Nd}_{1-x}\text{Bi}_x)_{0.5}\text{MoO}_4$  ceramics can be easily adjusted by changing the content of Bi. The low sintering temperature and chemical compatibility with aluminum powders, suggest that  $\text{K}_{0.5}(\text{Nd}_{1-x}\text{Bi}_x)_{0.5}\text{MoO}_4$  ceramics are candidates for ultra-low temperature co-fired ceramics technology.

## 4. CONCLUSIONS

$\text{K}_{0.5}(\text{Nd}_{1-x}\text{Bi}_x)_{0.5}\text{MoO}_4$  ( $0.2 \leq x \leq 0.7$ ) ceramics were prepared via solid state reaction method. Optimal density for  $\text{K}_{0.5}(\text{Nd}_{1-x}\text{Bi}_x)_{0.5}\text{MoO}_4$  ( $0.2 \leq x \leq 0.7$ ) ceramics decreased from 720 °C for  $x = 0.2$  to 580 °C for  $x = 0.7$  with no change in the grain size (1 ~ 3  $\mu\text{m}$ ).  $\epsilon_r$  of  $\text{K}_{0.5}(\text{Nd}_{1-x}\text{Bi}_x)_{0.5}\text{MoO}_4$  ( $0.2 \leq x \leq 0.7$ ) ceramics increased linearly from 13.6 at  $x = 0.2$  to 26.2 at  $x = 0.7$  while the Qf decreased from 23,400 GHz to 8,620 GHz. The best MW properties were obtained for  $x = 0.3$  (sintered at 660 °C) and 0.4 (sintered at 620 °C) with  $\epsilon_r \sim 15.4$ , Qf  $\sim 19,650$  GHz and TCF  $\sim -15$  ppm/°C, and  $\epsilon_r \sim 17.3$ , Qf  $\sim 13,050$  GHz and TCF  $\sim +4$  ppm/°C, respectively. This novel solid solution ceramic is a candidate for (U)LTCC technology.

## Acknowledgements

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Table I. Sintering temperatures and microwave dielectric properties of LTCC materials with permittivity between 15.2 ~ 17.5

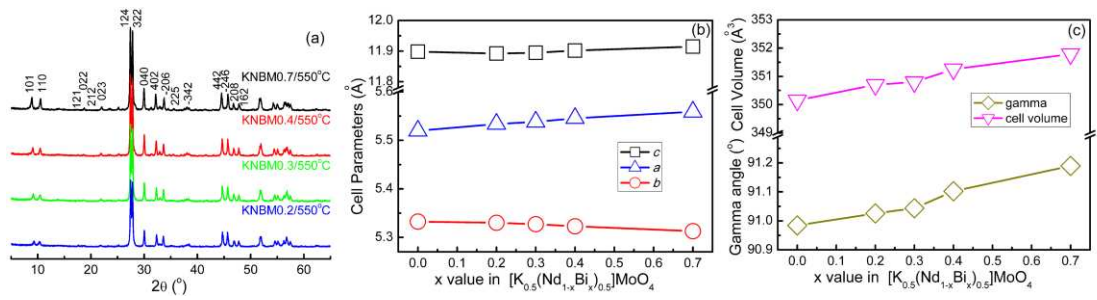
Composition	Sintering Temperature	$\epsilon_r$	Qf value (GHz)	TCF Value (ppm/ $^{\circ}$ C)	Ref.
CeTe <sub>2</sub> O <sub>6</sub>	680	15.2	45,400	-68	26
K <sub>0.5</sub> (Nd <sub>0.35</sub> Bi <sub>0.15</sub> )MoO <sub>4</sub>	660	15.4	19,650	-15	This work
Cu <sub>3</sub> Nb <sub>2</sub> O <sub>8</sub>	900	15.6	48,400	-75	27
Pb <sub>2</sub> WO <sub>5</sub>	520	16.4	14,800	-95	28
CoCu <sub>2</sub> Nb <sub>2</sub> O <sub>8</sub>	985	16.6	36,800	-37	29
ZnCu <sub>2</sub> Nb <sub>2</sub> O <sub>8</sub>	900	16.7	41,000	-77	29
K <sub>0.5</sub> (Nd <sub>0.3</sub> Bi <sub>0.2</sub> )MoO <sub>4</sub>	620	17.3	13,050	+4	This work
BaTe <sub>4</sub> O <sub>9</sub>	500	17.5	54,700	-90	9

## Figure Captions:

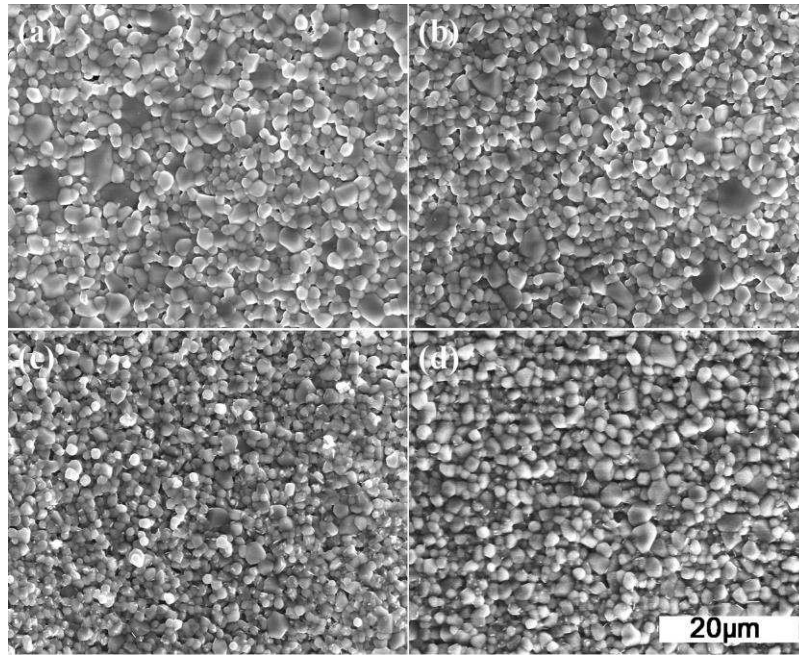
**FIGURE 1** XRD patterns of the  $[\text{K}_{0.5}(\text{Nd}_{1-x}\text{Bi}_x)_{0.5}]\text{MoO}_4$  samples ( $x = 0.2, 0.3, 0.4$  and  $0.7$ ) calcined at  $550\text{ }^\circ\text{C}$  for 4 h (a) and their cell parameters (b) and (c)

**FIGURE 2** SEM images of the  $[\text{K}_{0.5}(\text{Nd}_{1-x}\text{Bi}_x)_{0.5}]\text{MoO}_4$  ceramics sintered at  $720\text{ }^\circ\text{C}$  for  $x = 0.2$  (a), at  $660\text{ }^\circ\text{C}$  for  $x = 0.3$  (b), at  $600\text{ }^\circ\text{C}$  for  $x = 0.4$  (c) and at  $580\text{ }^\circ\text{C}$  for  $x = 0.7$  (d)

**FIGURE 3** Microwave dielectric permittivity (a) and Qf values (b) of the  $[\text{K}_{0.5}(\text{Nd}_{1-x}\text{Bi}_x)_{0.5}]\text{MoO}_4$  ( $x = 0.2, 0.3, 0.4$  and  $0.7$ ) ceramics as a function of sintering temperature and composition

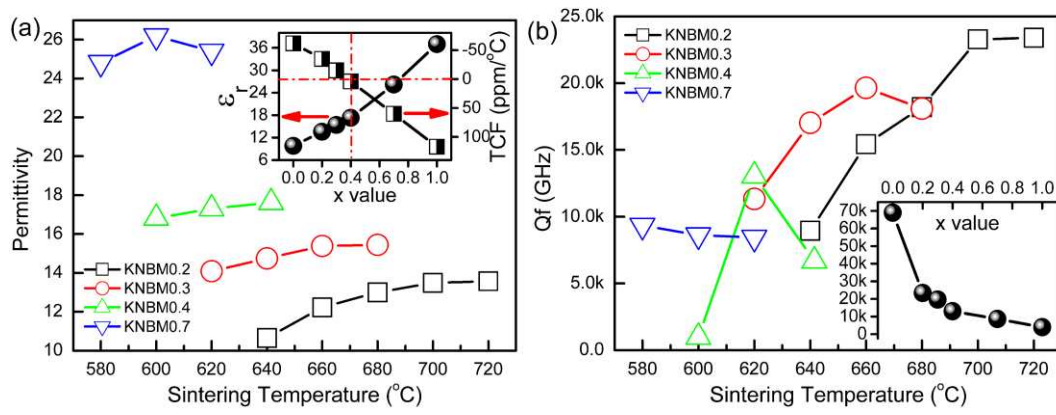


**FIGURE 1** XRD patterns of the  $[K_{0.5}(Nd_{1-x}Bi_x)_{0.5}]MoO_4$  samples ( $x = 0.2, 0.3, 0.4$  and  $0.7$ ) calcined at  $550\text{ }^\circ\text{C}$  for 4 h (a) and their cell parameters (b) and (c)



**FIGURE 2** SEM images of the  $[K_{0.5}(Nd_{1-x}Bi_x)_{0.5}]MoO_4$  ceramics sintered at 720 °C for  $x = 0.2$  (a), at 660 °C for  $x = 0.3$  (b), at 600 °C for  $x = 0.4$  (c) and at 580 °C for  $x = 0.7$  (d)





**FIGURE 3** Microwave dielectric permittivity (a) and Qf values (b) of the  $[\text{K}_{0.5}(\text{Nd}_{1-x}\text{Bi}_x)_{0.5}]\text{MoO}_4$  ( $x = 0.2, 0.3, 0.4$  and  $0.7$ ) ceramics as a function of sintering temperature and composition